

**207.1 - Scanning Electron Microscope (SEM)**

These RMs are for calibrating the magnification scale and evaluating the performance of scanning electron microscopes.

RM 8091 is used in checking the sharpness performance of scanning electron microscopes.

PLEASE NOTE: The tables are presented to facilitate comparisons among a family of materials to help customers select the best SRM for their needs. For specific values and uncertainties, the certificate is the only official source.

SRM	Description	Unit Size
8091	Scanning Electron Microscope Sharpness Standard	each
8820	Scanning Electron Microscope Scale Calibration Artifact	each
9952	Aluminum Drop-In Wafer Sample Holder for RM 8091 (200 mm)	each

- Certified values are normal font  
- Reference values are italicized  
- Values in parentheses are for information only